

# SUSS MicroTec's Asia Seminar Series 2007, Singapore

Date : 26<sup>th</sup> Oct 2007

Venue : York Hotel, Carlton Hall

Jointly Organized by :



## STREAMLINING THE DEVELOPMENT CYCLE

- Using Advanced Wafer-level Test Techniques  
to Overcome Today's Challenges

Presented by  
Industry Leaders :



Time	Synopsis	Speaker
0900hr – 0930hr :	Seminar Registration	
0930hr – 0945hr :	Opening Speech	Desmond LIM SUSS MicroTec
0945hr – 1030hr :	SUSS' MicroTec's Innovative ProbeShield Technology - the foundation for accurate on-wafer device characterization	Andrej RUMIANTSEV SUSS MicroTec
1030hr – 1045hr :	-- Tea Break --	
1045hr – 1130hr :	Flicker Noise & WLR Modeling Solutions	YANG Lian Feng ProPlus Design Solutions
1130hr – 1215hr :	Accurate Impedance Characterization - Getting the best out of your test equipment	Andrej RUMIANTSEV SUSS MicroTec
1215hr – 1315hr :	-- Lunch --	
1315hr – 1400hr :	Multiport Balanced Differential Measurements	TAN Hock Leong Anritsu
1400hr – 1445hr :	Addressing the Trend Towards Long-term, Wafer-level Reliability Measurements	Stojan KANEV SUSS MicroTec
1445hr – 1500hr :	-- Tea Break --	
1500hr – 1545hr :	Introduction of Keithley's Automated Characterization Suite (ACS)	CHEONG Siong Keat Keithley Instruments



The Next Generation of On-wafer Probing Architecture

Register by **15 Oct 2007** :  
Email Yvonne at [yvonne\\_loh@zmc.net](mailto:yvonne_loh@zmc.net)

## Biographies

### **Stojan KANEV**

*Director of Marketing  
SUSS MicroTec*



Stojan holds a Ph.D. in Electronic & Electrical Engineering from the Technical University in Dresden (Germany). He joined SUSS MicroTec in 1995 within the Test Division's product management group and has held various positions since. After launching the ProbeShield technology products in 1996, he quickly moved into the sales organization and eventually became manager of the direct sales channel covering strategic regions of Europe. Since 2005 Stojan has held the World Wide Director of Marketing position for the Test System Division.

### **Andrej RUMIANTSEV**

*Application Manager  
SUSS MicroTec*



Andrej was born in Minsk, Belarus in 1972. He received the Diploma-Engineer degree (with highest honors) in telecommunication systems and the Research-Engineer degree in electrical engineering from the Belarusian State University of Informatics and Radio Electronics in Minsk, Belarus. Andrej joined SUSS MicroTec's Test Systems Division in Dresden as a RF & Microwave Application Specialist, and currently as the Application Group Manager. His current research interests include calibration and wafer-level measurement techniques for new generation RF and Microwave semiconductor devices.

### **CHEONG Siong Keat**

*Senior Application Engineer  
Keithley Instruments International  
Corporation (Singapore)*



SK Cheong is involved in designing and building many testers for low level measurement in a major part of his career. With his experience in Operations and Research & Development, he is aware of the unique test requirements for each function and will generally give interesting solutions. SK currently reside in Singapore providing Application Support for South-East Asia. He has a Patent Pending to his name.

### **YANG Lian Feng**

*General Manager  
ProPlus Design Solutions, Inc*



Dr Yang is the General Manager of the Beijing R&D Center. Prior to joining ProPlus, Dr. Yang was a Senior Product Engineer for the Advanced Device Modeling product line at Cadence. He co-founded one company focused on IC design in 1999. Dr. Yang earned his Ph.D. degree in E.E. from University of Glasgow, UK, and has published ~40 technical papers in international conferences and journals.

### **TAN Hock Leong**

*Regional Marketing Manager  
Anritsu*



Hock Leong spends most part of his career in Test & Measurements. He is now based in Shanghai supporting customers in Asia.